



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Jun Koyama et al. Art Unit : 2822
Serial No. : 10/803,965 Examiner : Kiesha L. Rose
Filed : March 19, 2004
Title : SEMICONDUCTOR DEVICE AND MANUFACTURING METHOD THEREOF

MAIL STOP AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450.

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §§1.97 AND 1.98

Applicants would like to bring the Examiner's attention to the reference listed on the attached form PTO-1449. It is respectfully requested the reference listed on the attached form PTO-1449 be considered by the Examiner and that the document be initialed and returned to the undersigned.

This statement is being filed after a first Office action on the merits, but before receipt of a final Office action or a Notice of Allowance. A check for \$180 in payment of the late submission fee of C.F.R. § 1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06 1050.

Respectfully submitted,

Date: 2/9/05



John F. Hayden
Reg. No. 37,640

Customer No. 26171
Fish & Richardson P.C.
1425 K Street, N.W. - 11th Floor
Washington, DC 20005-3500
Telephone: (202) 783-5070
Facsimile: (202) 783-2331
JFH/adt
40266170.doc

02/11/2005 DTESSEN1 00000048 10803965

01 FC:1806

180.00 0P

Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
07977-209004Application No.
10/803,965**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

(37 CFR §1.98(b))

Applicant
Jun Koyama et al.Filing Date
March 19, 2004Group Art Unit
2822**U.S. Patent Documents**

| Examiner Initial | Desig. ID | Document Number | Publication Date | Patentee | Class | Subclass | Filing Date If Appropriate |
|------------------|-----------|-----------------|------------------|-----------------|-------|----------|----------------------------|
| | AA | 5,636,329 | 06/03/1997 | Sukegawa et al. | | | 06/22/1995 |
| | AB | | | | | | |
| | AC | | | | | | |
| | AD | | | | | | |
| | AE | | | | | | |
| | AF | | | | | | |
| | AG | | | | | | |
| | AH | | | | | | |
| | AI | | | | | | |
| | AJ | | | | | | |
| | AK | | | | | | |

Foreign Patent Documents or Published Foreign Patent Applications

| Examiner Initial | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation | |
|------------------|-----------|-----------------|------------------|--------------------------|-------|----------|-------------|----|
| | | | | | | | Yes | No |
| | AL | | | | | | | |
| | AM | | | | | | | |
| | AN | | | | | | | |
| | AO | | | | | | | |
| | AP | | | | | | | |

Other Documents (include Author, Title, Date, and Place of Publication)

| Examiner Initial | Desig. ID | Document |
|------------------|-----------|----------|
| | AQ | |
| | AR | |
| | AS | |
| | AT | |

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.